SDLS006

D2634, JANUARY 1981 REVISED MARCH 1988

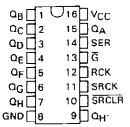
- 8-Bit Serial-In, Parallel-Out Shift Registers with Storage
- Choice of 3-State ('LS595) or Open-Collector ('LS596) Parallel Outputs
- Shift Register Has Direct Clear
- Accurate Shift Frequency: DC to 20 MHz

description

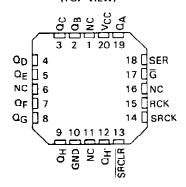
These devices each contain an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. The storage register has parallel 3-state ('LS595) or open-collector ('LS596) outputs. Separate clocks are provided for both the shift register and the storage register. The shift register has a direct-overriding clear, serial input, and serial output pins for cascading.

Both the shift register and storage register clocks are positive-edge triggered. If the user wishes to connect both clocks together, the shift register state will always be one clock pulse ahead of the storage register.

SN54LS595, SN54LS596...J OR W PACKAGE SN74LS595, SN74LS596...N PACKAGE (TOP VIEW)

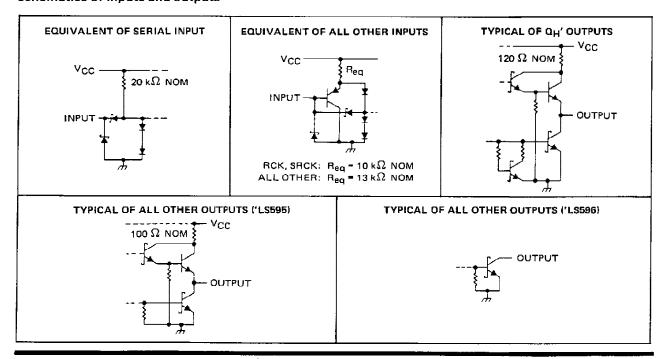


SN54LS595, SN54LS596 . . . FK PACKAGE (TOP VIEW)



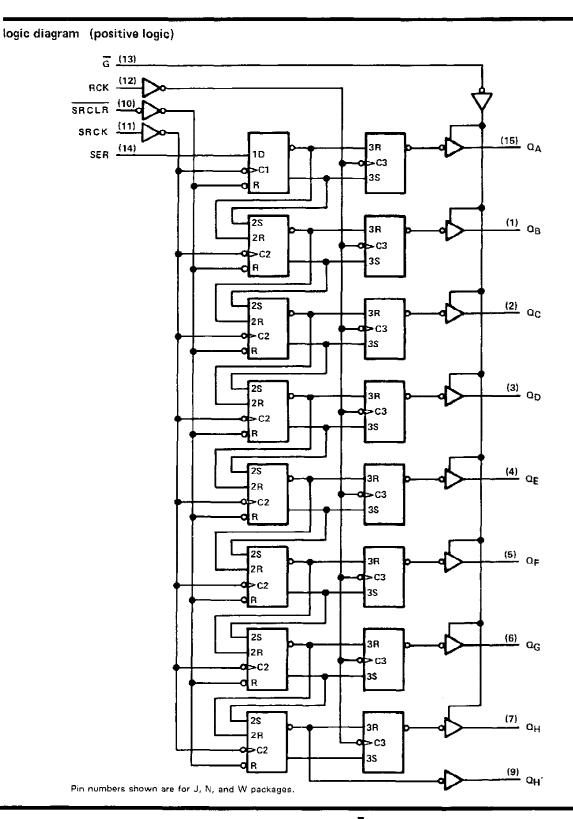
NC - No internal connection

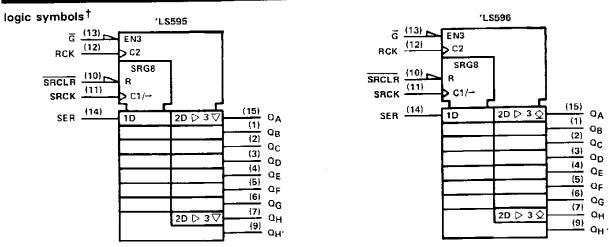
schematics of inputs and outputs



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 $^{^{\}dagger}$ These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for J, N, and W packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, Vcc (see Note 1)		
Input voltage		
Offictate output voltage		5.5 V
Operation free-air temperature range:	: SN54LS595.SN54LS596	55 C to 125 C
	SN741 S595, SN74LS596	0°C to /0°C
Storage temperature range		– 65°C to 150°C

NOTE 1: Voltage values are with respect to the network ground terminal.

recommended operating conditions

			SN54LS'			SN74LS'			UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
V _{CC}	Supply voltage		4.5	5	5.5	4.75	5	5.25	٧	
VIH	High-level input voltage		2			2			V	
VIL	Low-level input voltage				0.7			0.8	V	
VOH	High-level output voltage	QA thru QH, 'LS596 only			5.5			5.5	٧	
10Н		QH,			- 1_			-1	mA	
	High-level output current	Q _A thru Q _H , 'L\$595 only			- 1			– 2. 6		
loL	Low-level output current	QH'			8			16	mA	
		α			12			24		
fSRCK	Shift clock frequency		0		20	0		20	MH2	
tw(SRCK)	Duration of shift clock pulse		25			25			ns	
tw(RCK)	Duration of register clock pulse		20			20			ns	
tw(SRCLR)						20			ns	
		SRCLR inactive before SRCK 1	20			20				
	Setup time	SER before SRCK t	20			20			ns	
		SRCK † before RCK † (see Note 2)	40			40				
		SRCLR low before RCK t	40		-	40				
th	Hold time	SER after SRCK 1	0			0			ns	
TA	Operating free-air temperature				125	0		70	°C	

NOTE 2: This setup time ensures the register will see stable data from the shift-register outputs. The clocks may be connected together, in which case the storage register state will be one clock pulse behind the shift register.



SN54LS595, SN54LS596, SN74LS595, SN74LS596 8-BIT SHIFT REGISTERS WITH OUTPUT LATCHES

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER TEST CONDITIONS †		NITIONS T	SN54LS'			SN74LS'				
FARA	FARAMICIES TEST CONDITIONS		MIN	TYP#	MAX	MIN	TYP\$	MAX	UNIT	
V _{1K} V _{CC} = MIN, I ₁ = - 18 mA						- 1.5			– 1.5	V
∨он	'LS595 Q	V _{CC} = MIN, V _{IH} = 2 V,	lOH = − 1 mA	2.4	3.2					
		V _{II} = MAX	I _{OH} 2.6 mA				2.4	3.1		V
	OΗ,		1 _{OH} = -1 mA	2.4	3.2		2.4	3.2		
IOH	'LS596 Q	V _{CC} = MIN, V _{IH} = 2 V, V _I				0.1			0.1	mΑ
	α		I _{OL} ÷ 12 mA		0.25	0.4	Ţ	0.25	0.4	
_	V _{CC} = MIN, V _{IH} = 2 V,	I _{OL} = 24 mA					0.35	0.5	lv	
*UL	Vol.	· -	10L = 8 mA		0.25	0.4		0.25	0.4	,
^Q H′	(TH)		I _{OL} ≈ 16 mA					0.35	0,5	
^I OZH	'LS595 Q	VCC = MAX, VIH = 2 V, VI	L = MAX, V _{OH} = 2.7 V			20			20	μA
^I OZL	'LS595 Q	V _{CC} = MAX, V _{IH} = 2 V, V _I	L = MAX, VOH = 0.4 V			- 20			- 20	μА
I ₁		V _{CC} = MAX, V _I = 7 V				0.1			0.1	mA
Чн	_	V _{CC} - MAX, V ₁ - 2.7 V				20			20	μΑ
1	SER	VMAY V -64V				- 0.4			- 0.4	^
IIL All of	All others	VCC = MAX, V1 = 0.4 V			- 0.2			- 0.2	πA	
1 2	'L\$595 Q	W		- 30		130	- 30		- 130	
lOs §	QH'	$V_{CC} = MAX, V_{O} = 0 V$	- 20			- 100	- 20		- 100	mΑ
1	'LS595	<u> </u>			33	50		33	50	
CCH	'LS596	V _{CC} = MAX,		30	45		30	45	mΑ	
1	'LS595	All possible inputs grounded,		_	42	65		42	65	
ICCF	'L\$596	All outputs open			36	55		36	55	mA
¹ccz	'L\$595		j		44	65		44	65	mΑ

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions,

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.
§ Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

SN54LS595, SN54LS596, SN74LS595, SN74LS596 8-BIT SHIFT REGISTERS WITH OUTPUT LATCHES

switching characteristics, VCC = 5 V, TA = 25° C (see note 3)

PARAMETER	FROM	TO (OUTPUT)	TEST CONDITIONS		'LS595			'LS596			UNIT
	(INPUT)				MIN	TYP	MAX	MIN	TYP	MAX	UNI
tPLH	SRCK†		R _L = 1kΩ,	C _L = 30 pF		12	18		14	21	ns
^t PHL		QH'				17	25		20	30	ns
^t PLH	RCK†	Q _A thru Q _H	R _L = 667 Ω,	C _L = 45 pF	1	12	18		28	42	ns
^t PHL						24	35		24	35	ns
tPZH		Q _A thru Q _H				20	30				ns
tPZL						25	38				ns
^t PHZ	<u>G</u> ↑	Q _A thru Q _H	R _L = 667 Ω,	CL = 5 pF		20	30				ns
tPLZ	4 6 7	QA thru QH				25	38				ns
tPLH .	Ğ١	Qд thru Qн	$R_L = 667 \Omega$,	C _L = 45 pF			·		40	60	ns
tPHL	Ğ∔	Q _A thru Q _H							25	38	ns
^t PHL	SRCLR +	QH'	$R_{L} = 1 k\Omega$,	CL = 30 pF		24	35		24	35	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

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